

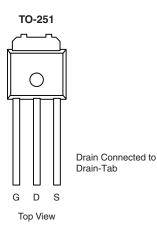
N-Channel 250 V (D-S) 175 °C MOSFET

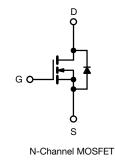
PRODUCT SUMMARY					
V _{DS} (V)	250				
R _{DS(on)} (Ω)	V _{GS} = 10 V	0.176			
Q _g max. (nC)	68				
Q _{gs} (nC)	11				
Q _{gd} (nC)	35				
Configuration	Single				

FEATURES

- Dynamic dV/dt rating
- Repetitive avalanche rated
- · Fast switching
- Ease of paralleling
- Simple drive requirements







ABSOLUTE MAXIMUM RATINGS ($T_C = 25 \text{ °C}$, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	250	V	
Gate-Source Voltage			V _{GS}	± 20		
Continuous Drain Current	V_{GS} at 10 V $T_{C} = 25^{\circ}$ $T_{C} = 100^{\circ}$	T _C = 25 °C	- I _D	17		
		T _C = 100 °C		11	А	
Pulsed Drain Current ^a			I _{DM}	56	1	
Linear Derating Factor				1.0	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	550	mJ	
Repetitive Avalanche Current ^a			I _{AR}	17	A	
Repetitive Avalanche Energy ^a			E _{AR}	13	mJ	
Maximum Power Dissipation	T _C = 25 °C			125	W	
Peak Diode Recovery dV/dt ^c			dV/dt	4.8	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	- °C	
Soldering Recommendations (Peak temperature) ^d	for 10 s			300		
Marine Tanana	6-32 or M3 screw			10	lbf ∙ in	
Mounting Torque				1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50$ V, starting $T_J = 25$ °C, L = 4.5 mH, $R_g = 25 \Omega$, $I_{AS} = 14$ A (see fig. 12). c. $I_{SD} \le 14$ A, dI/dt ≤ 150 A/µs, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C. d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.0		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		-		•	•	•	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA		250	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.34	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	١	$V_{GS} = \pm 20 \text{ V}$		-	± 100	nA
Zone Ooto Vielto en Durin Ourmont		$V_{DS} = 250 \text{ V}, V_{GS} = 0 \text{ V}$		-	-	25	μA
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 200 V	V _{DS} = 200 V, V _{GS} = 0 V, T _J = 125 °C		-	250	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 8.4 A ^b	-	0.176	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	50 V, I _D = 8.4 A ^b	6.7	-	-	S
Dynamic		-		•	•	•	
Input Capacitance	C _{iss}		$V_{GS} = 0 V,$	-	1300	-	
Output Capacitance	C _{oss}		$V_{\text{GS}} = 0.7$, $V_{\text{DS}} = 25 \text{ V}$,		330	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1.	0 MHz, see fig. 5	-	85	-	1
Total Gate Charge	Qg			-	-	68	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 7.9 \text{ A}, V_{DS} = 200 \text{ V},$ see fig. 6 and 13 ^b		-	11	
Gate-Drain Charge	Q _{gd}			-	-	35	1
Turn-On Delay Time	t _{d(on)}	V_{DD} = 125 V, I _D = 7.9 A, R _g = 9.1 Ω , R _D = 8.7 Ω , see fig. 10 ^b		-	11	-	- ns
Rise Time	t _r			-	24	-	
Turn-Off Delay Time	t _{d(off)}			-	53	-	
Fall Time	t _f			-	49	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from		-	4.5	-	nH
Internal Source Inductance	L _S	package and o die contact	package and center of		7.5	-	
Gate Input Resistance	R _g	f = 1 MHz, open drain		0.3	-	1.2	Ω
Drain-Source Body Diode Characteristic		•		•	•	•	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	14	_
Pulsed Diode Forward Current ^a	I _{SM}			-	-	56	A
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 14 A, V _{GS} = 0 V ^b		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	$T_{\rm J} = 25 ^{\circ}\text{C}, I_{\rm F} = 7.9 \text{A}, \text{dl/dt} = 100 \text{A/}\mu\text{s}^{\text{b}}$		-	250	500	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	2.3	4.6	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)					L _D)

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

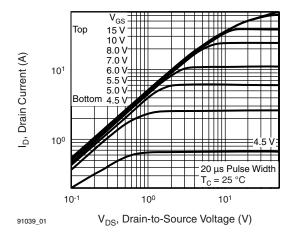


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

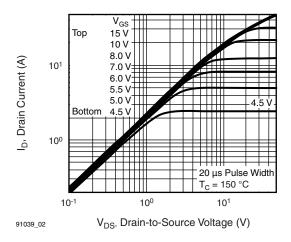


Fig. 2 - Typical Output Characteristics, $T_C = 150 \ ^\circ C$

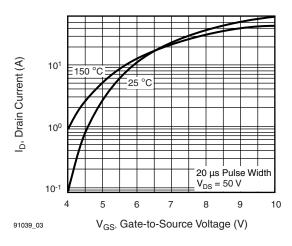


Fig. 3 - Typical Transfer Characteristics

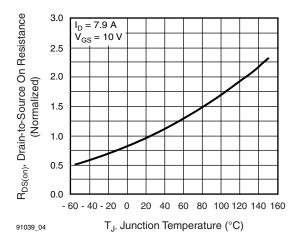


Fig. 4 - Normalized On-Resistance vs. Temperature

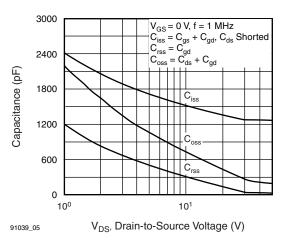


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

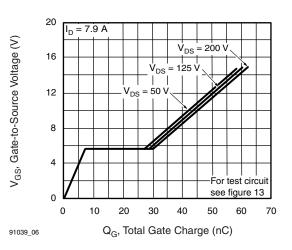


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

FU12N25D

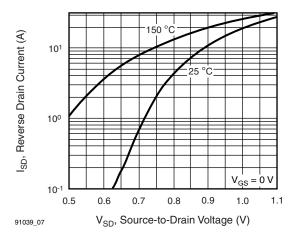


Fig. 7 - Typical Source-Drain Diode Forward Voltage

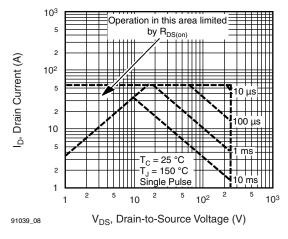


Fig. 8 - Maximum Safe Operating Area

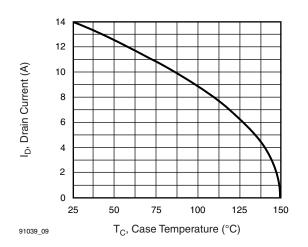


Fig. 9 - Maximum Drain Current vs. Case Temperature

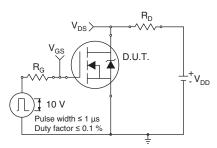


Fig. 10a - Switching Time Test Circuit

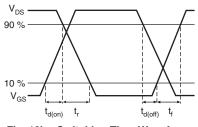


Fig. 10b - Switching Time Waveforms

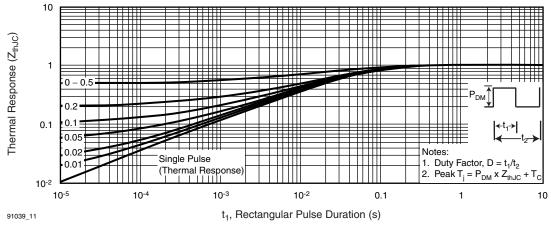


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



FU12N25D

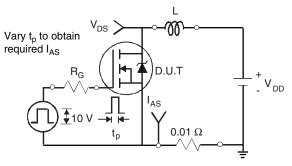
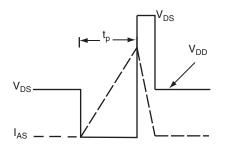


Fig. 12a - Unclamped Inductive Test Circuit



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Fig. 12b - Unclamped Inductive Waveforms

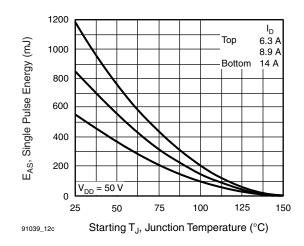


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

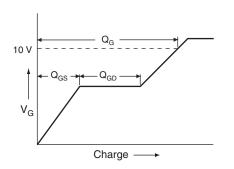


Fig. 13a - Basic Gate Charge Waveform

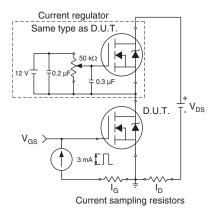
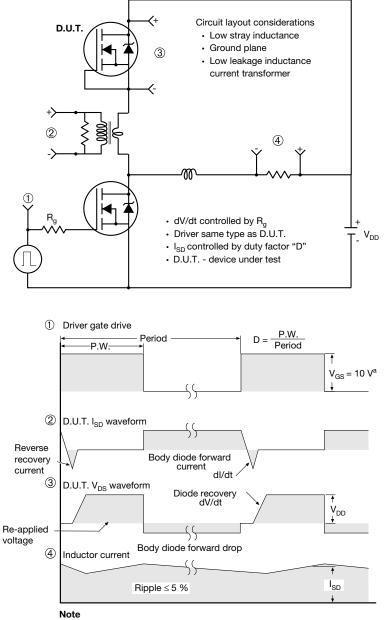


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

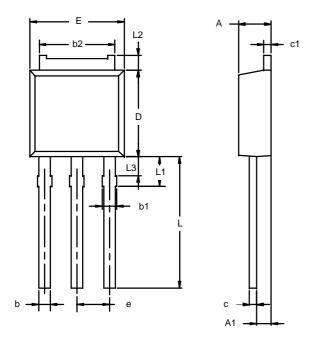


a. V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel



TO-251AA (DPAK)



	MILLIM	IETERS	INCHES		
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
A1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
c1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
E	6.48	6.73	0.255	0.265	
е	2.28	BSC	0.090	BSC	
L	3.89	9.53	0.153	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	

Note: Dimension L3 is for reference only.



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